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E. Villio
7-10-02

Docket: 740756-2406

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Divisional Patent Application of)
Shunpei YAMAZAKI et al.)
Based On Serial No. 09/172,300) Art Unit: 2813
Which Was Filed: October 14, 1998) Examiner: E. Pert
For: METHOD OF MANUFACTURING)
A SEMICONDUCTOR DEVICE) Date: January 15, 2002



INFORMATION DISCLOSURE STATEMENT

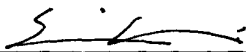
Honorable Commissioner for Patents and Trademarks
Washington, D.C. 20231

Sir:

In accordance with the provisions of 37 C.F.R. 1.56 and 37 C.F.R. 1.97-1.99,
it is requested that the references listed on the attached Form PTO-1449 be made of
record in the above-identified application.

The references listed on the attached Form PTO-1449 were cited in parent
application Serial No. 09/172,300 filed October 14, 1998.

Respectfully submitted,


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Form PTO-1449 (Rev. 8-83)	U.S. Department of Commerce Patent and Trademark Office	Docket No. 740756-2406	Serial No. Not Yet Assigned
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			
		Applicant: Shunpei YAMAZAKI et al.	
		Filing Date: January 15, 2002	Group: 2813

1050 U.S. PTO
 10/044926
 01/15/02

U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	5,648,277	07/15/1997	Zhang et al.			
	5,643,826	07/01/1997	Ohtani et al.			
	6,124,154	09/26/2000	Miyasaka			
	5,550,070	08/27/1996	Funai et al.			

FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation Yes No
	08-078329	03/22/1996	Japan			Abstract
	07-321339	12/08/1995	Japan			Abstract
	07-130652	05/19/1995	Japan			Abstract
	07-135318	05/23/1995	Japan			Abstract
	05-109737	04/30/1993	Japan			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
	R. Shimokawa and Y. Hayashi, "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758

Examiner	Date Considered
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	